

100364 Low Power 16-Input Multiplexer

General Description

The 100364 is a 16-input multiplexer. Data paths are controlled by four Select lines (S_0 – S_3). Their decoding is shown in the truth table. Output data polarity is the same as the selected input data. All inputs have 50 k Ω pulldown resistors.

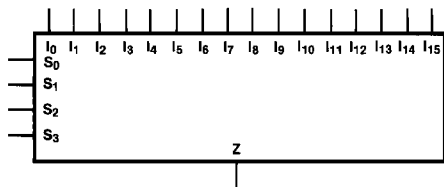
- 2000V ESD protection
- Pin/function compatible with 100164
- Voltage compensated operating range = $-4.2V$ to $-5.7V$
- Available to industrial grade temperature range
- Available to MIL-STD-883

Features

- 35% power reduction of the 100164

Ordering Code:

Logic Symbol

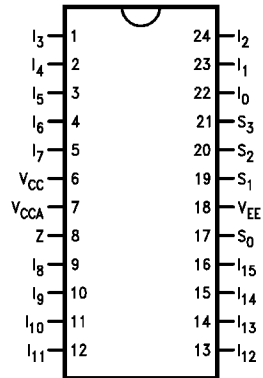


DS010265-1

Pin Names	Description
I_0 – I_{15}	Data Inputs
S_0 – S_3	Select Inputs
Z	Data Output

Connection Diagrams

24-Pin DIP



DS010265-2

Truth Table

Select Inputs				Output
S ₀	S ₁	S ₂	S ₃	Z
L	L	L	L	I ₀
H	L	L	L	I ₁
L	H	L	L	I ₂
H	H	L	L	I ₃
L	L	H	L	I ₄
H	L	H	L	I ₅
L	H	H	L	I ₆
H	H	H	L	I ₇
L	L	L	H	I ₈
H	L	L	H	I ₉
L	H	L	H	I ₁₀
H	H	L	H	I ₁₁
L	L	H	H	I ₁₂
H	L	H	H	I ₁₃
L	H	H	H	I ₁₄
H	H	H	H	I ₁₅

H = HIGH Voltage Level
L = LOW Voltage Level

Absolute Maximum Ratings (Note 1)

Above which the useful life may be impaired

Storage Temperature (T_{STG})	-65°C to +150°C
Maximum Junction Temperature (T_J)	
Ceramic	+175°C
Plastic	+150°C
Pin Potential to Ground Pin (V_{EE})	-7.0V to +0.5V
Input Voltage (DC)	V_{EE} to +0.5V
Output Current (DC Output HIGH)	-50 mA
ESD (Note 2)	≥ 2000V

Recommended Operating Conditions

Case Temperature (T_C)	
Commercial	0°C to +85°C
Industrial	-40°C to +85°C
Military	-55°C to +125°C
Supply Voltage (V_{EE})	-5.7V to -4.2V

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Commercial Version DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = 0^\circ C$ to $+85^\circ C$ (Note 1)

Symbol	Parameter	Min	Typ	Max	Units	Conditions	
V_{OH}	Output HIGH Voltage	-1025	-955	-870	mV	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to -2.0V
V_{OL}	Output LOW Voltage	-1830	-1705	-1620	mV		
V_{OHC}	Output HIGH Voltage	-1035			mV	$V_{IN} = V_{IH}$ (Min) or V_{IL} (Max)	Loading with 50Ω to -2.0V
V_{OLC}	Output LOW Voltage			-1610	mV		
V_{IH}	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs	
V_{IL}	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs	
I_{IL}	Input LOW Current	0.5			μA	$V_{IN} = V_{IL}$ (Min)	
I_{IH}	Input HIGH Current			300	μA	$V_{IN} = V_{IH}$ (Max)	
I_{EE}	Power Supply Current	-89		-45	mA	Inputs Open	

Note 3: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operate under "worst case" conditions.

DIP AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH}	Propagation Delay	0.90	2.00	0.90	2.00	0.90	2.10	ns	Figures 1, 2
t_{PHL}	I_0-I_{15} to Output								
t_{PLH}	Propagation Delay	1.40	2.80	1.40	2.80	1.50	2.90		
t_{PHL}	S_0, S_1 to Output								
t_{PLH}	Propagation Delay	1.00	2.20	1.00	2.20	1.10	2.40		
t_{PHL}	S_2, S_3 to Output								
t_{TLH}	Transition Time	0.35	1.20	0.35	1.20	0.35	1.20	ns	
t_{THL}	20% to 80%, 80% to 20%								

PCC and Cerpak AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH}	Propagation Delay	0.90	1.80	0.90	1.80	0.90	1.90	ns	
t_{PHL}	I_0-I_{15} to Output								

PCC and Cerpak AC Electrical Characteristics (Continued)

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH}	Propagation Delay	1.40	2.60	1.40	2.60	1.50	2.70	ns	Figures 1, 2
t_{PHL}	S_0, S_1 to Output								
t_{PLH}	Propagation Delay	1.00	2.00	1.00	2.00	1.10	2.20	ns	
t_{PHL}	S_2, S_3 to Output								
t_{TLH}	Transition Time	0.35	1.10	0.35	1.10	0.35	1.10	ns	
t_{THL}	20% to 80%, 80% to 20%								

Industrial Version PCC DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -40^\circ C$ to $+85^\circ C$ (Note 6)

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = 0^\circ C$ to $+85^\circ C$		Units	Conditions	
		Min	Max	Min	Max			
V_{OH}	Output HIGH Voltage	-1085	-870	-1025	-870	mV	$V_{IN} = V_{IH}$ (Max)	Loading with 50Ω to $-2.0V$
V_{OL}	Output LOW Voltage	-1830	-1575	-1830	-1620	mV	or V_{IL} (Min)	
V_{OHC}	Output HIGH Voltage	-1095		-1035		mV	$V_{IN} = V_{IH}$ (Min)	Loading with 50Ω to $-2.0V$
V_{OLC}	Output LOW Voltage		-1565		-1610	mV	or V_{IL} (Max)	
V_{IH}	Input HIGH Voltage	-1170	-870	-1165	-870	mV	Guaranteed HIGH Signal for All Inputs	
V_{IL}	Input LOW Voltage	-1830	-1480	-1830	-1475	mV	Guaranteed LOW Signal for All Inputs	
I_{IL}	Input LOW Current	0.5		0.5		μA	$V_{IN} = V_{IL}$ (Min)	
I_{IH}	Input HIGH Current		325		325	μA	$V_{IN} = V_{IH}$ (Max)	
I_{EE}	Power Supply Current	-89	-45	-89	-45	mA	Inputs Open	

Note 4: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 5: ESD testing conforms to MIL-STD-883, Method 3015.

Note 6: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

PCC AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH}	Propagation Delay	0.90	1.80	0.90	1.80	0.90	1.90	ns	Figures 1, 2
t_{PHL}	I_0-I_{15} to Output								
t_{PLH}	Propagation Delay	1.20	2.60	1.40	2.60	1.50	2.70	ns	
t_{PHL}	S_0, S_1 to Output								
t_{PLH}	Propagation Delay	0.80	2.10	1.00	2.00	1.10	2.20	ns	
t_{PHL}	S_2, S_3 to Output								
t_{TLH}	Transition Time	0.20	1.20	0.35	1.10	0.35	1.10	ns	
t_{THL}	20% to 80%, 80% to 20%								

Military Version DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^{\circ}C$ to $+125^{\circ}C$

Symbol	Parameter	Min		Max		Units	T_C	Conditions		Notes
V_{OH}	Output HIGH Voltage	-1025	-870			mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	(Notes 7, 8, 9)
		-1085	-870			mV	$-55^{\circ}C$			
V_{OL}	Output LOW Voltage	-1830	-1620			mV	$0^{\circ}C$ to $+125^{\circ}C$			
		-1830	-1555			mV	$-55^{\circ}C$			
V_{OHC}	Output HIGH Voltage	-1035				mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Min) or V_{IL} (Max)	Loading with 50Ω to $-2.0V$	(Notes 7, 8, 9)
		-1085				mV	$-55^{\circ}C$			
V_{OLC}	Output LOW Voltage		-1610			mV	$0^{\circ}C$ to $+125^{\circ}C$			
			-1555			mV	$-55^{\circ}C$			
V_{IH}	Input HIGH Voltage	-1165	-870			mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed HIGH Signal for All Inputs		(Notes 7, 8, 9, 10)
V_{IL}	Input LOW Voltage	-1830	-1475			mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed LOW Signal for All Inputs		(Notes 7, 8, 9, 10)
I_{IL}	Input LOW Current	0.50				μA	$-55^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -4.2V$ $V_{IN} = V_{IL}$ (Min)	(Notes 7, 8, 9)	
I_{IH}	Input HIGH Current		300			μA	$0^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH}$ (Max)	(Notes 7, 8, 9)	
			450			μA	$-55^{\circ}C$			
I_{EE}	Power Supply Current	-95	-35			mA	$-55^{\circ}C$ to $+125^{\circ}C$	Inputs Open		(Notes 7, 8, 9)

Note 7: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 8: Screen tested 100% on each device at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups, 1, 2, 3, 7 and 8.

Note 9: Sampled tested (Method 5005, Table I) on each manufactured lot at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups A1, 2, 3, 7 and 8.

Note 10: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^{\circ}C$		$T_C = 25^{\circ}C$		$T_C = +125^{\circ}C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t_{PLH}	Propagation Delay	0.50	2.60	0.60	2.40	0.60	2.80	ns	Figures 1, 2	(Notes 11, 12, 13)
t_{PHL}	$I_0 - I_{15}$ to Output									
t_{PLH}	Propagation Delay	0.70	3.30	0.90	3.10	1.00	3.50	ns		
t_{PHL}	S_0, S_1 to Output									
t_{PLH}	Propagation Delay	0.50	2.90	0.70	2.60	0.60	3.00	ns		
t_{PHL}	S_2, S_3 to Output									
t_{TLH}	Transition Time	0.20	1.20	0.20	1.20	0.20	1.20	ns	(Note 14)	
t_{THL}	20% to 80%, 80% to 20%									

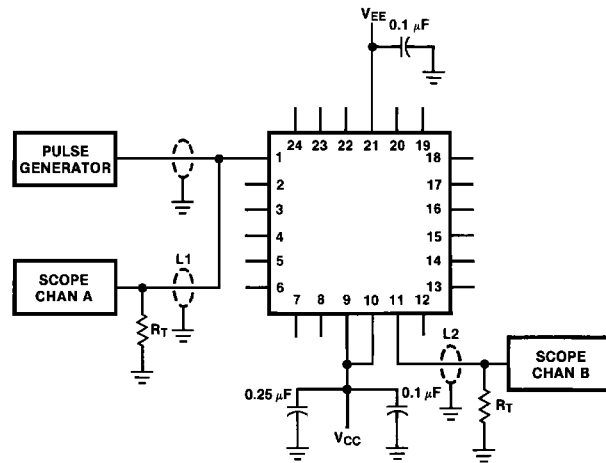
Note 11: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 12: Screen tested 100% on each device at $+25^{\circ}C$, temperature only, Subgroup A9.

Note 13: Sample tested (Method 5005, Table I) on each Mfg. lot at $+25^{\circ}C$, Subgroup A9, and at $+125^{\circ}C$, and $-55^{\circ}C$ temp., Subgroups A10 and A11.

Note 14: Not tested at $+25^{\circ}C$, $+125^{\circ}C$ and $-55^{\circ}C$ temperature (design characterization data).

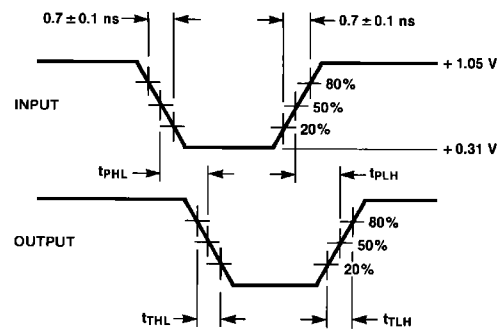
Test Circuit



DS010265-6

FIGURE 1. AC Test Circuit

Switching Waveforms



DS010265-7

Note 15: V_{CC} , $V_{CCA} = +2V$, $V_{EE} = -2.5V$

Note 16: L1 and L2 = Equal length 50Ω impedance lines

Note 17: $R_T = 50\Omega$ terminator internal to scope

Note 18: Decoupling 0.1 μF from GND to V_{CC} and V_{EE}

Note 19: All unused outputs are loaded with 50Ω to GND

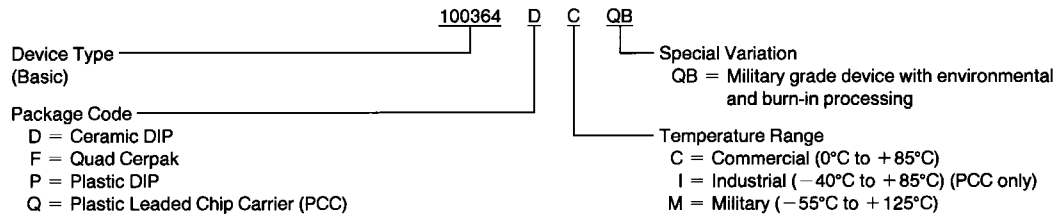
Note 20: C_L = Fixture and stray capacitance ≤ 3 pF

Note 21: Pin numbers shown are for flatpak; for DIP see logic symbol

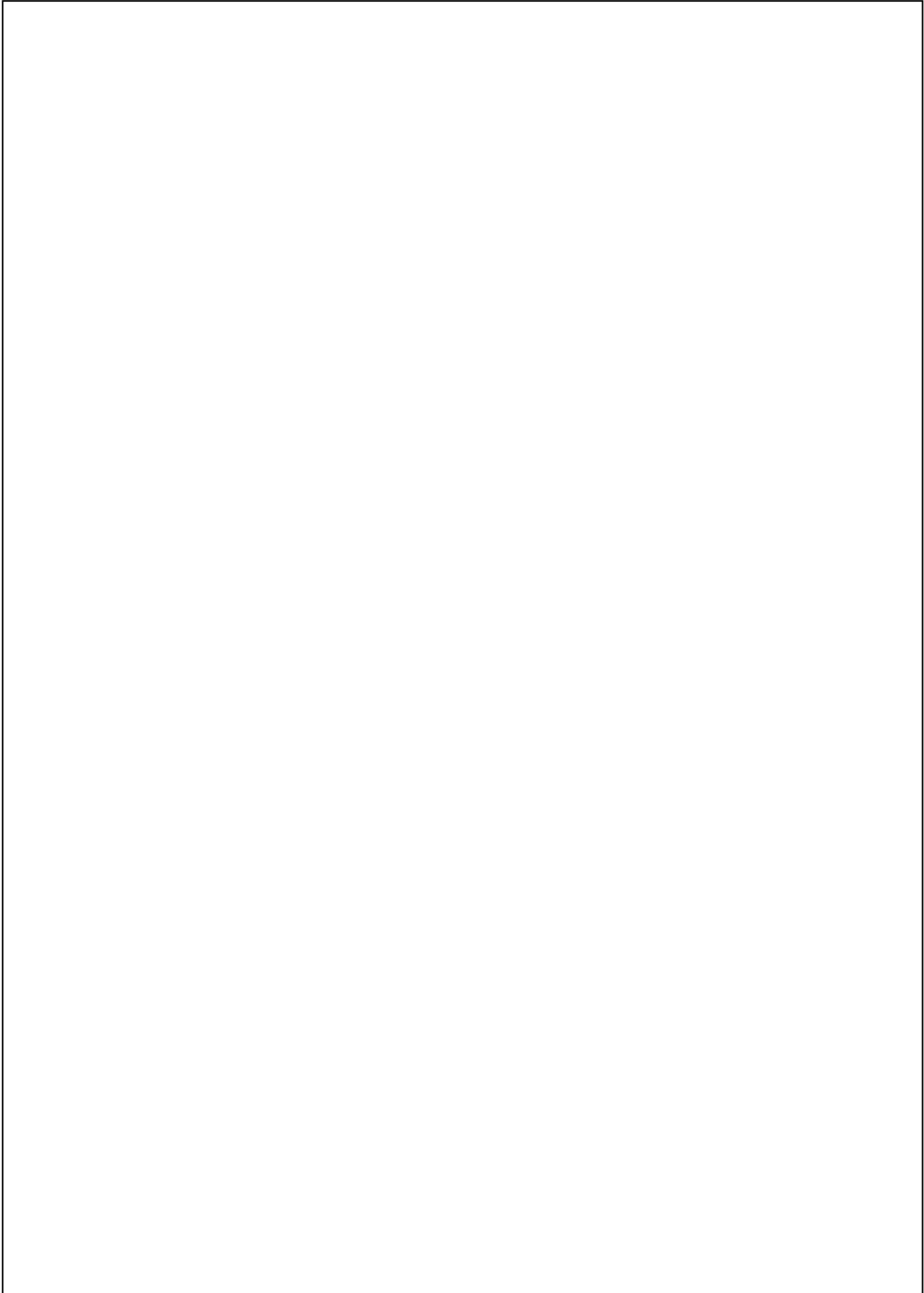
FIGURE 2. Propagation Delay and Transition Times

Ordering Information

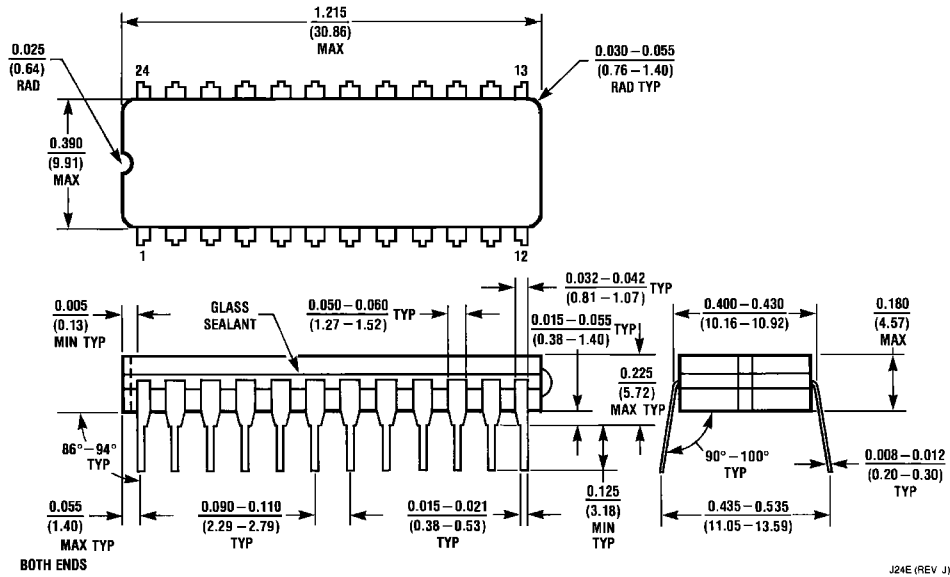
The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:



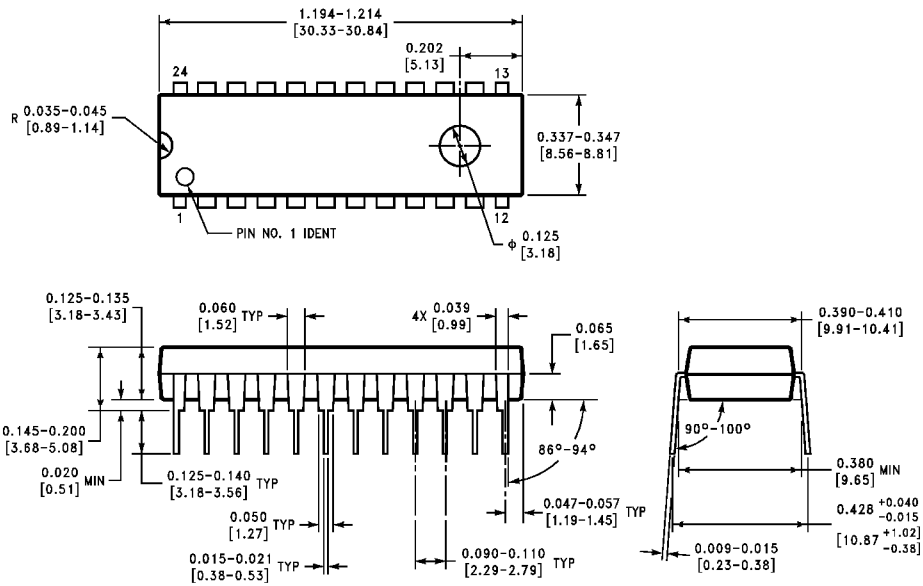
DS010295-8



Physical Dimensions inches (millimeters) unless otherwise noted

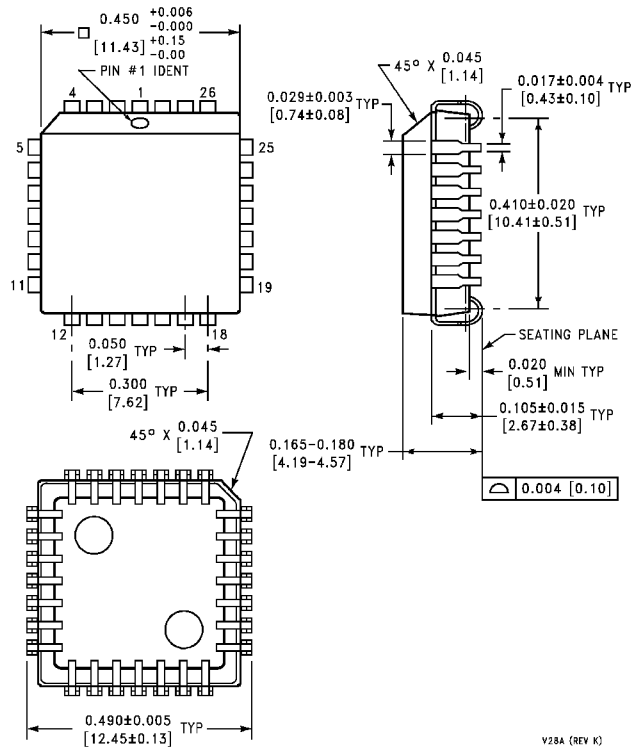


J24E (REV J)



N24E (REV A)

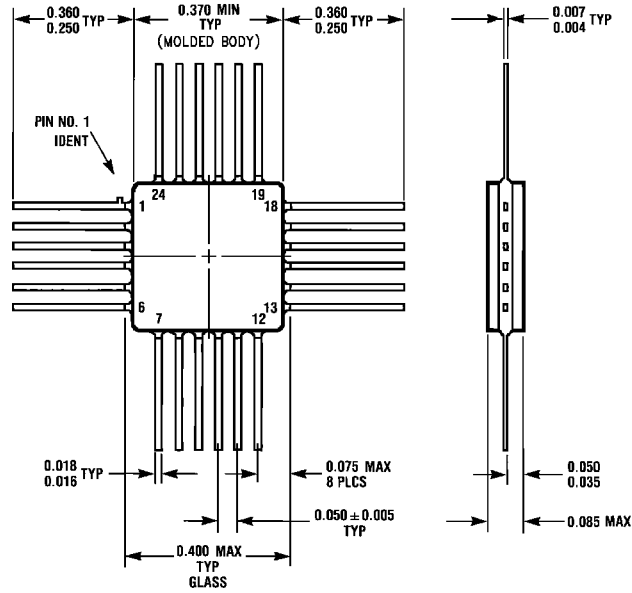
Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



28-Lead Plastic Chip Carrier (Q)
Package Number V28A

V28A (REV K)

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



W24B (REV D)

**24-Lead Quad Cerpak (F)
Package Number W24B**

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Fairchild Semiconductor Corporation
Americas
Customer Response Center
Tel: 1-888-522-5372

Fairchild Semiconductor Europe
Fax: +49 (0) 1 80-530 85 86
Email: europe.support@nsc.com
Deutsch Tel: +49 (0) 8 141-35-0
English Tel: +44 (0) 1 793-85-68-56
Italy Tel: +39 (0) 2 57 5631

Fairchild Semiconductor Hong Kong Ltd.
13th Floor, Straight Block,
Ocean Centre, 5 Canton Rd.
Tsimshatsui, Kowloon
Hong Kong
Tel: +852 2737-7200
Fax: +852 2314-0061

National Semiconductor Japan Ltd.
Tel: 81-3-5620-6175
Fax: 81-3-5620-6179

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